



SNR252012 Series, an automatic assembly constructed power inductor, is shielded with magnetic resin





◆特征:

- 磁性胶水涂敷结构极大减少了蜂鸣声
- 大电流低直流阻抗
- 直接在磁芯上金属化电极,抗跌落冲击强 经久耐用
- 闭合磁路结构设计,漏磁少,抗 EMI 能力强
- 省空间,更省电
- 符合 RoHS,无卤和 REACH

◆用途:

● 广泛应用于 LED 背光板、平板电视、 蓝光 DVD 机顶盒、笔记本电脑、台式电脑、 服务器、显卡、便携式游戏机、个人导航系统、 多媒体、汽车产品 、通信设备、直流转换.

◆环境:

工作温度: -40℃ 至+125℃
 (包括线圈自身温升)

◆试验设备:

- 电感值:HP4284A, HP4285A 或同等仪器
- 电流:HP4284+42841A 或同等仪器
- 直流电阻: Chroma 16502 或同等仪器

252012

R68

Features:

- Magnetic-resin shielded construction reduces buzz
 Noise to ultra-low levels
- Large Current and Low DCR
- Metallization on Ferrite Core results in excellent shock Resistance and damage-free durability
- Closed magnetic circuit design reduces leakage
 Flux and Electro Magnetic Interference (EMI)
- Takes up less PCB real estate and save more power Small parasitic capacitance
- RoHS, Halogen Free and REACH Compliance

Applications:

LED backlight、Flat-screen TVs, blue-ray disc
 Set top box、Notebooks, desktop computers, servers,
 Graphic cards、Portable gaming devices, personal
 Navigation systems, personal multimedia devices,
 Automotive systemsTelecomm base station、DC-DC
 Converter

Environmental Data:

Operating Temperature: -40°C to +125°C
 (Including coils self-temperature rise)

Test Equipment:

- L:HP4284A or HP4285A LCR meter or equivalent
- Isat & Irms: HP4284+42841A or equivalent
- DCR:Chroma 16502 or equivalent

Product Identification:

◆产品型号:

SNR

1	2	3
1	lit.	_
	类型 Type	
1111	闭磁路贴片电感	
SNR	Shielded SMD Power Inductors	1

	2	<i>Y</i>
	外形尺寸(L:	×W×H) (mm)
	External Dimer	nsions (L×W×H)
是	(m	nm)
	252012	2.5×2.0×1.2

3	
Inductance	
0.68 uH	
	_





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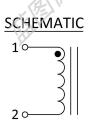
公差 Inductance Tolerance

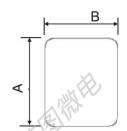
J:±5%,K: ±10%, L: ±15% M: ±20%,P: ±25%, N: ±30% ⑤

包装 Packing		
В	散装Bulk Package	
T 编带Tape & Reel		

◆外观尺寸:

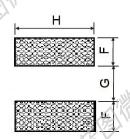
Shape and Dimensions(dimensions are in mm):











Recommended

Land Pattern

Part No			K	ITE	М		n (E)	
Faltivo	Α	В	C	D	Е	F	G	Н
SNR252012	2.5±0.2	2.0±0.2	1.2 Max	0.8±0.2	1.5±0.2	0.85 Typ	0.8 Typ	2.0 Typ

◆规格特性:

Specifications:

• SNR252012 Series Electrical Characteristics (Electrical specifications at 25℃)

Dord No.	Induct 100KHz		DC	CR (Ω)	Saturation Current	Temperature Rise Current	
Part No	L(μH) '@0A	Typical		Max	(A) Max	(A) Max	
SNR252012-R68NT	0.68	±3 0 %	0.059	0.074	3.28	1.95	
SNR252012-1R0NT	1.0	±30%	0.072	0.090	2.59	1.93	
SNR252012-1R5MT	1.5	±20%	0.117	0.147	2.24	1.40	
SNR252012-2R2MT	2.2	±20%	0.173	0.216	1.85	1.15	
SNR252012-3R3MT	3.3	±20%	0.211	0.264	1.61	1.04	
SNR252012-4R7MT	4.7	±20%	0.302	0.377	1.12	0.84	
SNR252012-5R6MT	5.6	±20%	0.430	0.538	1.11	0.73	
SNR252012-6R8MT	6.8	±20%	0.464	0.581	0.98	0.69	
SNR252012-8R2MT	8.2	±20%	0.526	0.658	0.98	0.65	
SNR252012-100MT	10	±20%	0.552	0.690	0.79	0.62	
SNR252012-150MT	15	±20%	1.273	1.591	0.68	0.42	
SNR252012-220MT	22	±20%	1.459	1.824	0.53	0.38	

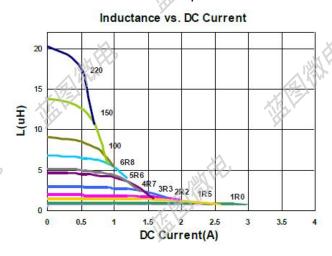
- Saturation Current: DC current at which inductance drops 30% from its value without current.
- Temperature Rise Current: the actual value of DC current when the temperature rise isΔT 40°C (Ta=25°C).
- Rated DC Current: The less value which is Isat or Irms.

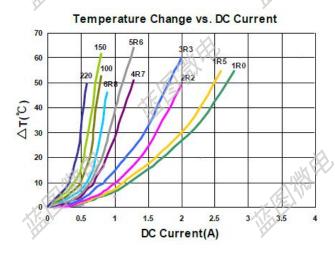






- Special remind:Circuit design, component, PCB trace size and thickness, airflow and other cooling provisions all affect the part temperature. Part temperature should be verified in the end application.
- Saturation current VS temperature rise current curve

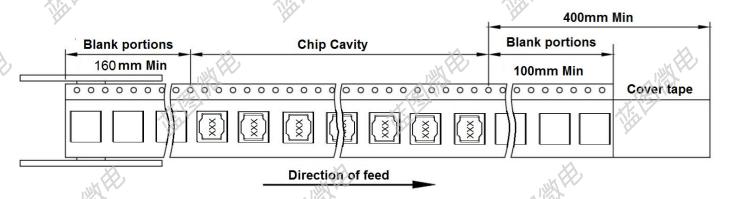




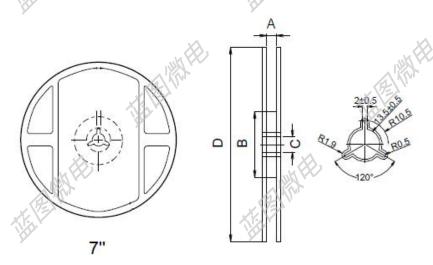
◆产品包装:

Packaging:

• Tape and Reel Specifications: (Dimensions are in mm)



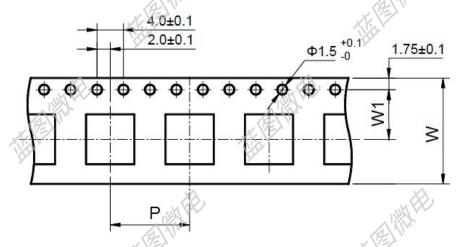
• Reel Dimensions (mm)





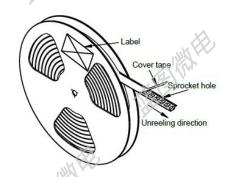


●Tape Dimension (mm)

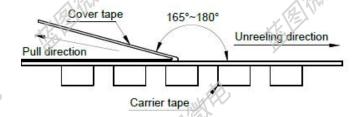


Part No.	Tape Dimension		Reel Dimensions			REEL	Inside	Outside		
Part No.	W	Р	W1	Α	В	С	D	(PCS)	Box(PCS)	Carton(PCS)
SNR252012	8	4	3.5	8.4	60	13	178	2000	20,000	80,000

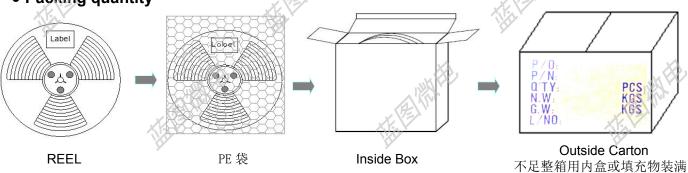
• Cover tape peel off condition



- a) Cover tape peel force shall be 10 to 120g
- b) Noodle strip peeling angle165° to 180°



Packing quantity







◆可靠性测试:

Reliability Testing:

Items	Requirements	Test Methods and Remarks
Terminal Strength Reference docu ments: GB/T 2423 60-2008 端子強度(SMT)	1. Pulling test: Define: A: sectional area of terminal A ≤ 8mm2 force ≥ 5N time:30sec 8mm2 <a 10n="" 10sec="" 2.solder="" 20mm2="" 20mm2<a="" 20n="" 3.meet="" above="" any="" force="" loose="" paste="" requirements="" td="" terminal<="" the="" thickness:0.12mm="" time:="" without="" ≤="" ≥=""><td>Solder the inductor to the testing jig using leadfree solder. Then apply a force in the Keep time: 10±1s Speed: 1.0mm/s.</td>	Solder the inductor to the testing jig using leadfree solder. Then apply a force in the Keep time: 10±1s Speed: 1.0mm/s.
erminal Strength Reference docu ments: GB/T 2423.60-2008 端子強度(DIP)		Pull Force:the force shall be applied gradually to the terminal and thenmaintained for 10 seconds. F Pulling test
Resistance to Flexure JIS C 5321:1997 抗弯曲性试验		1.Solder the inductor to the test jig (glass epoxy board 2.shown in Using a leadfree solder. Then apply a force in the direction shown 3.Flexure: 2mm. 4.Pressurizing Speed: 0.5mm/sec. 5.Keep time: 30 sec.
Dropping Reference documents:	X\7	1.Drop the packaged products from 1m high in 1 angle, 3 ridges and 6surfaces, twice in each
GB/T 2423.7-2018 落下試驗	·	direction.
Solderability Reference documents: GB/T 2423.28-2005 可焊性试验	3. Terminals must have 95% minimum solder	 1.Solder temperture:240±2℃ 2.Duration: 3 sec. 3. Solder: Sn/3.0Ag/0.5Cu. 4.Flux: 25% Resin and 75% ethanol in weight





Items	Requirements	Test Methods and Remarks
Vibration Reference documents:	1.No visible mechanical damage. 2. Inductance change: Within ±10%. 3.Q factor change: Within ±20%. Cu pad Solder mask	1.Solder the inductor to the testing jig (glass epoxy boardshown in) using leadfree solder. 2.The inductor shall be subjected to a simple harmonic motion having total amplitude of 1.5mm, the frequency being varieduniformly between the approximate limits of 10 and 55 Hz. 3.The frequency range from 10 to 55 Hz and return to 10 Hz shallbe traversed in approximately
GB/T 2423.10-2019 振動試验	Glass Epoxy Board	1 minute. This motion shall be applied for a period of 2 hours in each 3mutually perpendicular directions(total of 6 hours).
提展	提展機構	10Hz 0 1Min Time
Ÿ	1.No visible mechanical damage.	1.Start at (85~125℃) for T time, rush to
	Within ≦ 30%)	(-55~40°C) for T time as one cycle, go through100 cycles.
Thermal Shock	3.Q factor change: Within ±20%.	Z.Transforming interval: Max. 20 sec. 3.Tested cycle: 100 cycles.
Reference documents:	y y	4.The chip shall be stabilized at normal condition
GB/T 2423.22-2012 Method Na 冷热冲击试验	推提	for 1~2 hours 125°C/85°C Ambient Temperature -55°C/-40°C 30 min. 20sec. (max.)
	H	20sec. (max.)
	1.No visible mechanical damage.	1.Temperature:M(-55~-40±2℃)
	2. Inductance change: Within ±10%.(Mn-Zn:	2.Duration: 96±2 hours
Low temperature Storage	Within ≤ 30%)	3.The chip shall be stabilized at normal condition for
Reference documents:	3.Q factor change: Within ±20%.	1~2 hoursbefore measuring.
GB/T 2423.1-2008 Method Ab 低温储存试验	THE PART OF THE PA	Room Temp 0 96H Test 97H 98H Time Low temperature





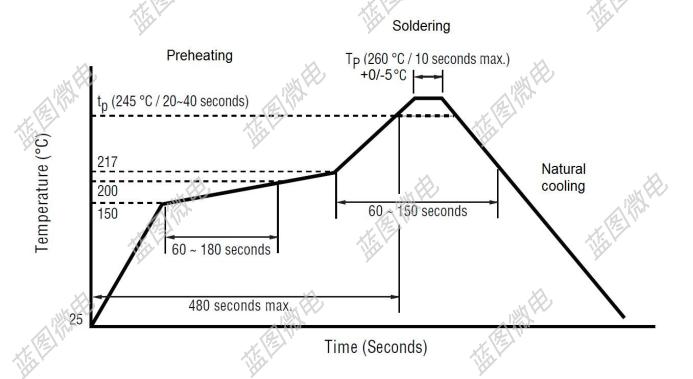
Items	Requirements	Test Methods and Remarks
	1.No visible mechanical damage.	1.Temperature:N(125~85±2℃).
High temperature	2. Inductance change: Within ±10%.(Mn-Zn:	2.Duration: 96±2 hours
Storage		3. The chip shall be stabilized at normal condition
	3.Q factor change: Within ±20%	for 1~2 hoursbefore measuring.
GB/T 2423.2-2008		Temp High temperature
Method Bb	· · · · · · · · · · · · · · · · · · ·	N°C
高温储存试验		Room
□□ □□□ □□ □□ □□□□□□□□□□□□□□□□□□□□□□□□		Test
		0 96H 97H 98H Time
	No visible mechanical damage.	1.Temperature: 60±2°C
	2. Inductance change: Within ±10%.(Mn-Zn.	1 XY ₂ Y
Damp Heat	Within ≦30%)	3.Duration: 96±2 hours.
(Steady States)	3.Q factor change: Within ±20%.	4. The chip shall be stabilized at normal condition
Reference documents:		for 1~2 hoursbefore measuring.
GB/T 2423.3-2016		Temp & Humidity
恒定湿热试验	A SEAN	93%RH High femorature High humidity
THE P	Tit.	Conditions
		0 96H 97H 98H Time
Heat endurance of	1.No significant defects in appearance.	1.Refer to the above reflow curve and go through
Reflow soldering	2. △ L/L ≦ 10% (Mn-Zn: △ L/L ≦ 30%)	the reflow for twice.
Reference documents:	3. △ Q/Q ≦ 30% (SMD series only)	2.The peak temperature : 260+0/-5℃
GJB 360B-2009	4, ∆ DCR/DCR≦10%	ji.
回流焊耐热性试验		· A
Resistance to solvent	No case deformation or change in	To dip parts into IPA solvent for 5±0.5Min,then
test	appearance or obliteration of marking	drying them at room temp for 5Min,at last ,to
Reference documents:	X Z	brushing making 10 times.
IEC 68-2-45:1993	ji.	W.
耐溶剂性试验		
Overland test	1.During the test no smoke, no peculiar,	THE THE STATE OF T
Overload test Reference documents:	A 11/A 1	A TOTAL OF THE PARTY OF THE PAR
	2.The characteristic is normal after test	Apply twice as rated current for 5 minutes.
010 00011 0.10	ED.	Ÿ
过负荷试验	1	
过负荷试验 voltage resistance test	1.During the test no breakdown	X
voltage resistance test	During the test no breakdown The characteristic is normal after test	- July HE
voltage resistance test	2.The characteristic is normal after test	1. For parts with two coils
voltage resistance test Reference documents:	2.The characteristic is normal after test	1. For parts with two coils 2. DC1000V, Current: 1mA, Time: 1Min. 3. Refer to catalogue of specific products





◆推荐回流焊温度曲线

Recommended reflow soldering curve:



The recommended reflow conditions as above graph, is set according to our soldering equipment. DUE to various manufactures may have different reflow soldering equipment, products, process conditions, set methods. And so on, when setting the reflow conditions, Please adjust and confirm according to users' environment/equipment.





使用注意事项

REMINDERS FOR USING THESE PRODUCTS



● 保存时间为12 个月以内,保存条件(温度5~40°C以下、湿度35 ~ 66%RH 以下),需充分注意 若超过保存时间,端子电极的可焊性将可能老化。

The storage period is within 12 months. Be sure to follow the storage conditions (temperature: 5~40°C, humidity: 35 to 65% RH or less). If the storage period elapses, the soldering of the terminal electrodes may deteriorate.

• 请勿在气体腐蚀环境(盐、酸、碱等)下使用和保存。

Do not use or store in locations where there are conditions such as gas corrosion (salt, acid, alkali, etc.).

- 手上的油脂会导致可焊性降低,应避免用手直接接触端子。
 - Don't touch electrodes directly with bare hands as oil secretions may inhibit soldering Always ensure optimum conditions for soldering.
- 请小心轻拿轻放,避免由于产品的跌落或取出不当而导致的损坏。
 - Please always handle products carefully to prevent any damage caused bydropping down or inappropriate removing.
- 端子过度弯曲会导致断线,请不要过度弯曲端子。
 Don't bend the terminals with excessive stress in case of any wire fracture。
- 不要清洗产品, 如需要清洗时请联系我司。
 - Don't rinse coils by yourself and please contact SXN if necessary.
- 请勿将本产品靠近磁铁或带有磁力的物体
 - Don't expose the products to magnets or magnetic fields
- 在实施焊接前,请务必进行预热。预热温度与焊接温度及芯片温度的温度差要在150°C 以内。 Before soldering, be sure to preheat components. The preheating temperature should be set so that the temperature difference between the solder temperature and chip temperature does not exceed 150°C.
- 安装后的焊接修正应在规格书规定的条件范围内。若加热过度可能导致短路、性能降低、寿命减少。 Soldering corrections after mounting should be within the range of the conditions determined in the specifications. If overheated, a short circuit, performance deterioration, or lifespan shortening may occur.
- 装置会因通电而自我发热(温度上升),因此在热设计方面需留有充分余地。
 Self heating (temperature increase) occurs when the power is turned ON, so the tolerance should be sufficient for the set thermal design.
- 非磁屏蔽型在基板设计时需注意配置线圈,受到电磁干扰可能会导致误动作。
 Carefully lay out the coil for the circuit board design of the non-magnetic shield type. A malfunction may occur due to magnetic interference.